# **IGBT**

This Insulated Gate Bipolar Transistor (IGBT) features a robust and cost effective Field Stop (FS) Trench construction, and provides superior performance in demanding switching applications, offering both low on state voltage and minimal switching loss. The IGBT is well suited for half bridge resonant applications. Incorporated into the device is a soft and fast co–packaged free wheeling diode with a low forward voltage.

#### **Features**

- Low Saturation Voltage using Trench with Fieldstop Technology
- Low Switching Loss Reduces System Power Dissipation
- Low Gate Charge
- Soft, Fast Free Wheeling Diode
- These are Pb-Free Devices

#### **Typical Applications**

- Inductive Heating
- Soft Switching

#### **ABSOLUTE MAXIMUM RATINGS**

Rating	Symbol	Value	Unit
Collector-emitter voltage	V <sub>CES</sub>	600	V
Collector current @ Tc = 25°C @ Tc = 100°C	I <sub>C</sub>	60 30	A
Pulsed collector current, T <sub>pulse</sub> limited by T <sub>Jmax</sub>	I <sub>CM</sub>	150	Α
Diode forward current @ Tc = 25°C @ Tc = 100°C	I <sub>F</sub>	60 30	А
Diode pulsed current, T <sub>pulse</sub> limited by T <sub>Jmax</sub>	I <sub>FM</sub>	150	Α
Gate-emitter voltage	$V_{GE}$	±20	V
Power Dissipation @ Tc = 25°C @ Tc = 100°C	P <sub>D</sub>	250 50	W
Operating junction temperature range	T <sub>J</sub>	-55 to +150	°C
Storage temperature range	T <sub>stg</sub>	-55 to +150	°C
Lead temperature for soldering, 1/8" from case for 5 seconds	T <sub>SLD</sub>	260	°C

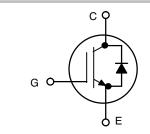
Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

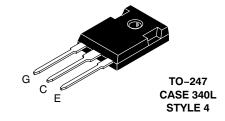


# ON Semiconductor®

http://onsemi.com

30 A, 600 V V<sub>CEsat</sub> = 1.8 V E<sub>off</sub> = 0.28 mJ





### **MARKING DIAGRAM**



A = Assembly Location

Y = Year WW = Work Week G = Pb-Free Package

### **ORDERING INFORMATION**

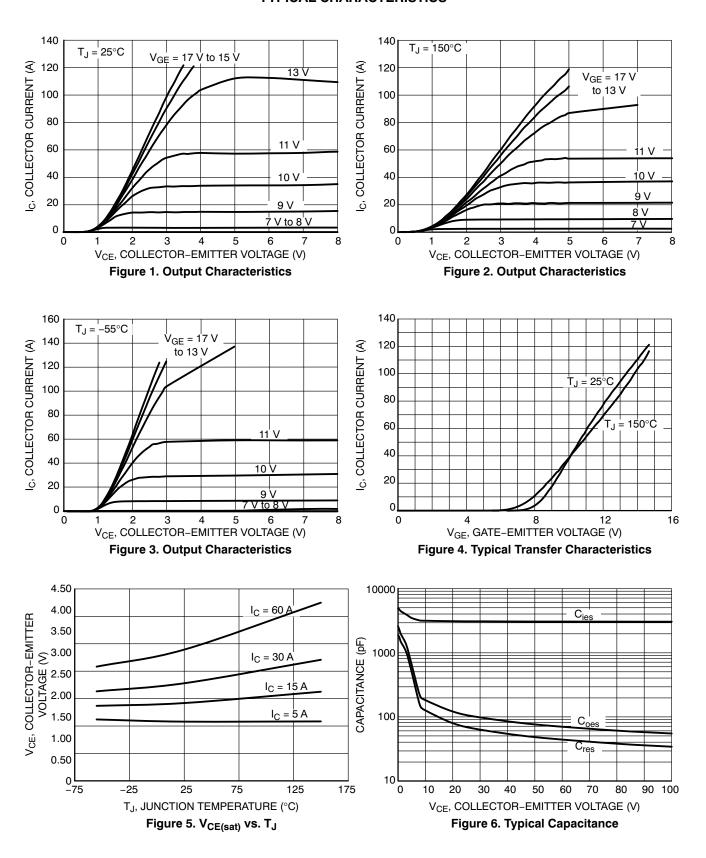
Device	Package	Shipping
NGTB30N60IHLWG	TO-247 (Pb-Free)	30 Units / Rail

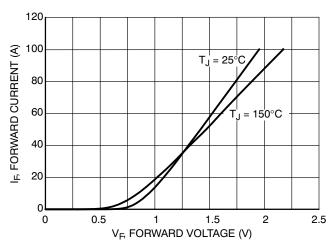
### THERMAL CHARACTERISTICS

Rating	Symbol	Value	Unit
Thermal resistance junction-to-case, for IGBT	$R_{ heta JC}$	0.87	°C/W
Thermal resistance junction-to-case, for Diode	$R_{ heta JC}$	1.46	°C/W
Thermal resistance junction-to-ambient	$R_{ heta JA}$	40	°C/W

# **ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Test Conditions	Symbol	Min	Тур	Max	Unit
STATIC CHARACTERISTIC	,					
Collector-emitter breakdown voltage, gate-emitter short-circuited	$V_{GE} = 0 \text{ V, I}_{C} = 500  \mu\text{A}$	V <sub>(BR)CES</sub>	600	_	-	V
Collector-emitter saturation voltage	V <sub>GE</sub> = 15 V, I <sub>C</sub> = 30 A V <sub>GE</sub> = 15 V, I <sub>C</sub> = 30 A, T <sub>J</sub> = 150°C	V <sub>CEsat</sub>	-	1.8 2.2	2.3 -	V
Gate-emitter threshold voltage	$V_{GE} = V_{CE}, I_{C} = 250 \mu A$	V <sub>GE(th)</sub>	4.5	5.5	6.5	V
Collector-emitter cut-off current, gate- emitter short-circuited	V <sub>GE</sub> = 0 V, V <sub>CE</sub> = 600 V V <sub>GE</sub> = 0 V, V <sub>CE</sub> = 600 V, T <sub>J</sub> = 150°C	I <sub>CES</sub>	-	- -	0.2 2	mA
Gate leakage current, collector-emitter short-circuited	V <sub>GE</sub> = 20 V , V <sub>CE</sub> = 0 V	I <sub>GES</sub>	_	-	100	nA
DYNAMIC CHARACTERISTIC	•	,		•	•	
Input capacitance		C <sub>ies</sub>	-	3100	-	pF
Output capacitance	V <sub>CE</sub> = 20 V, V <sub>GE</sub> = 0 V, f = 1 MHz	C <sub>oes</sub>	-	120	-	
Reverse transfer capacitance	7	C <sub>res</sub>	-	80	-	
Gate charge total		Qg		130		nC
Gate to emitter charge	V <sub>CE</sub> = 480 V, I <sub>C</sub> = 30 A, V <sub>GE</sub> = 15 V	Q <sub>ge</sub>		27		
Gate to collector charge		Q <sub>gc</sub>		65		
SWITCHING CHARACTERISTIC, INDUC	TIVE LOAD					
Turn-on delay time		t <sub>d(on)</sub>		70		ns
Rise time	T <sub>J</sub> = 25°C	t <sub>r</sub>		30		
Turn-off delay time	$V_{CC} = 400 \text{ V, } I_{C} = 30 \text{ A}$ $R_{g} = 10 \Omega$ $V_{GE} = 0 \text{ V/ } 15 \text{V}$	t <sub>d(off)</sub>		140		
Fall time	$V_{GE} = 0 \text{ V/ } 15 \text{V}$	t <sub>f</sub>		80		
Turn-off switching loss	1	E <sub>off</sub>		0.28		mJ
Turn-on delay time		t <sub>d(on)</sub>		70		ns
Rise time	T <sub>J</sub> = 150°C	t <sub>r</sub>		32		
Turn-off delay time	$V_{CC} = 400 \text{ V, } I_{C} = 30 \text{ A}$ $R_{g} = 10 \Omega$ $V_{GE} = 0 \text{ V/ } 15 \text{V}$	t <sub>d(off)</sub>		150		
Fall time		t <sub>f</sub>		100		
Turn-off switching loss	]	E <sub>off</sub>		0.55		mJ
DIODE CHARACTERISTIC				-	-	
Forward voltage	V <sub>GE</sub> = 0 V, I <sub>F</sub> = 30 A V <sub>GE</sub> = 0 V, I <sub>F</sub> = 30 A, T <sub>J</sub> = 150°C	V <sub>F</sub>		1.2 1.2	1.4	V
Reverse recovery time	T <sub>J</sub> = 25°C	t <sub>rr</sub>		400		ns
Reverse recovery charge	l <sub>F</sub> = 30 Å, V <sub>R</sub> = 200 V di <sub>F</sub> /dt = 200 A/μs	Q <sub>rr</sub>		4500		nc
Reverse recovery current	7	I <sub>rrm</sub>		23		Α





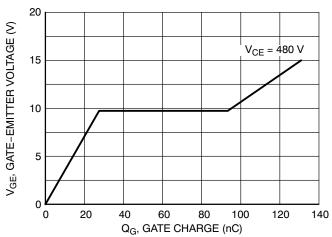


Figure 7. Diode Forward Characteristics

Figure 8. Typical Gate Charge

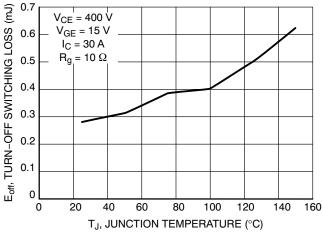


Figure 9. Switching Loss vs. Temperature

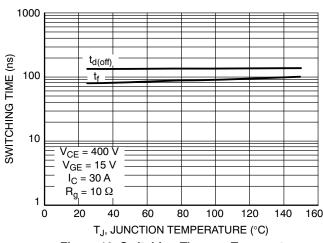


Figure 10. Switching Time vs. Temperature

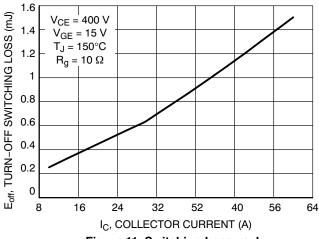


Figure 11. Switching Loss vs. I<sub>C</sub>

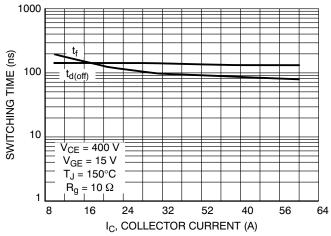


Figure 12. Switching Time vs. I<sub>C</sub>

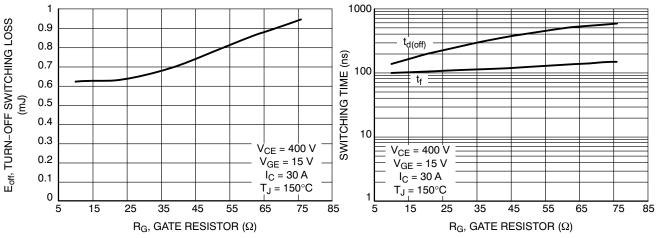


Figure 13. Switching Loss vs. R<sub>G</sub>

Figure 14. Switching Time vs. R<sub>G</sub>

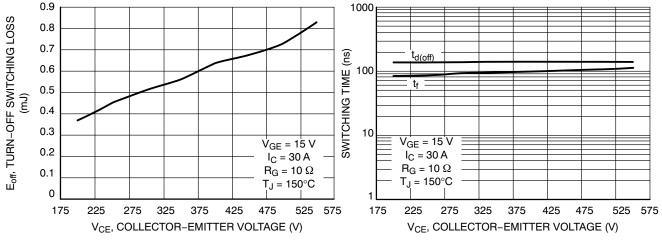


Figure 15. Switching Loss vs. V<sub>CE</sub>

Figure 16. Switching Time vs. V<sub>CE</sub>

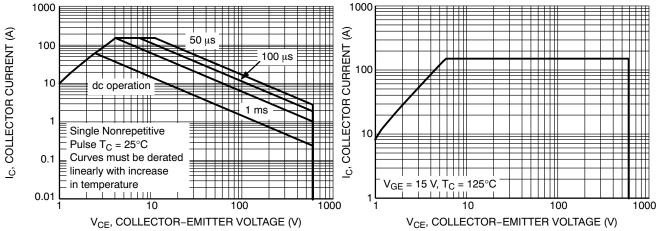


Figure 17. Safe Operating Area

Figure 18. Reverse Bias Safe Operating Area

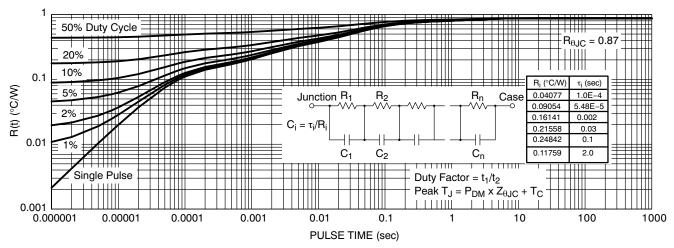


Figure 19. IGBT Transient Thermal Impedance

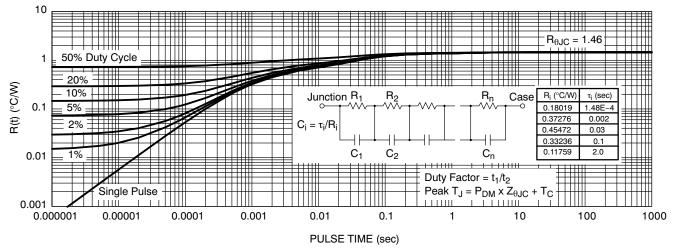


Figure 20. Diode Transient Thermal Impedance

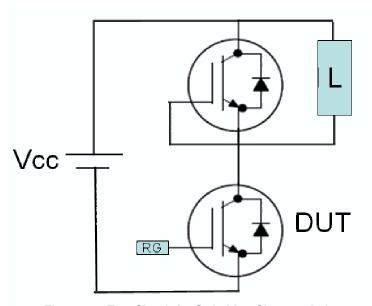


Figure 21. Test Circuit for Switching Characteristics

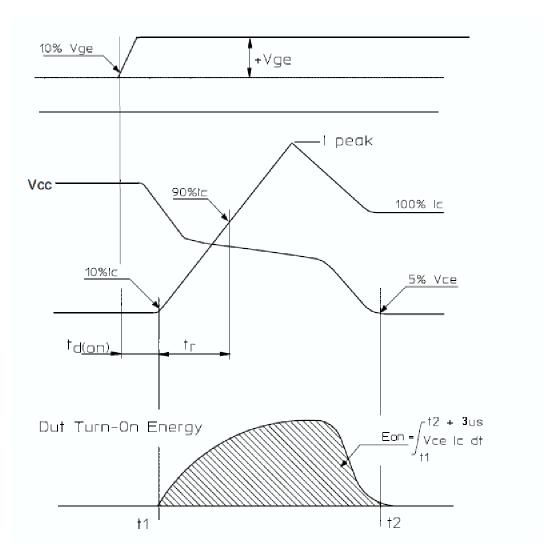


Figure 22. Definition of Turn On Waveform

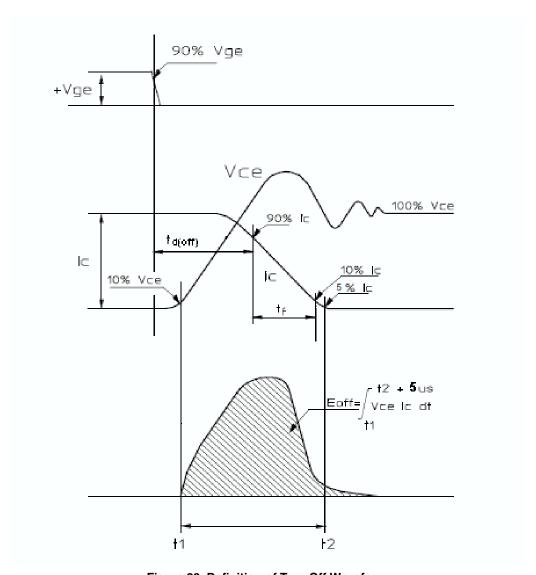
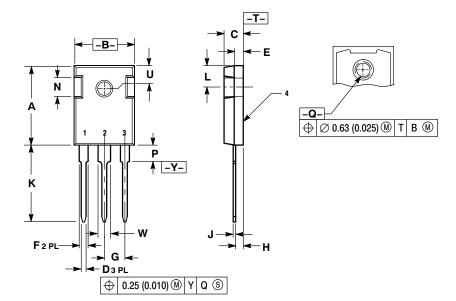


Figure 23. Definition of Turn Off Waveform

#### PACKAGE DIMENSIONS

TO-247 CASE 340L-02 ISSUE F



- DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
- 2. CONTROLLING DIMENSION: MILLIMETER.

	MILLIMETERS		INCHES		
DIM	MIN	MAX	MIN	MAX	
Α	20.32	21.08	0.800	8.30	
В	15.75	16.26	0.620	0.640	
С	4.70	5.30	0.185	0.209	
D	1.00	1.40	0.040	0.055	
Е	1.90	2.60	0.075	0.102	
F	1.65	2.13	0.065	0.084	
G	5.45 BSC		0.215 BSC		
Н	1.50	2.49	0.059	0.098	
J	0.40	0.80	0.016	0.031	
K	19.81	20.83	0.780	0.820	
L	5.40	6.20	0.212	0.244	
N	4.32	5.49	0.170	0.216	
P		4.50		0.177	
Q	3.55	3.65	0.140	0.144	
J	6.15	BSC	0.242 BSC		
w	2 87	3 12	0 113	0 123	

STYLE 4:

PIN 1. GATE 2. COLLECTOR 3. EMITTER

4. COLLECTOR

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